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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <small>(Not for submission under 37 CFR 1.99)</small>	Application Number		10536483
	Filing Date		2005-05-24
	First Named Inventor		Bruce B. Doris
	Art Unit		2826
	Examiner Name		Benjamin T. Liu
	Attorney Docket Number		6798

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Examiner Initial*	Cite No	Patent Number	Kind Code <sup>1</sup>	Issue Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines where Relevant Passages or Relevant Figures Appear	
BTL	1	6342410		2002-01-29	Yu		
BTL	2	6573172		2003-06-03	En et al.		
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Examiner Initial*	Cite No	Publication Number	Kind Code <sup>1</sup>	Publication Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines where Relevant Passages or Relevant Figures Appear	
BTL	1	20030040158		2003-02-27	Saitoh		
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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(Not for submission under 37 CFR 1.99)</i>	Application Number	10536483
	Filing Date	2005-05-24
	First Named Inventor	Bruce B. Doris
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	Examiner Name	Benjamin T. Liu
	Attorney Docket Number	6798

Examiner Initials*	Cite No	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc), date, pages(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>5</sup>
BTL	1	A. Shimizu et al., "Local Mechanical-Stress Control (LMC): A New Technique for CMOS-Performance Enhancement", International Electron Devices Meeting 2001. IEDM Technical Digest. 2001 IEEE, pp. 19.4.1-19.4.4.	<input type="checkbox"/>
BTL	2	S. Ito et al., "Effect of Mechanical Stress Induced by Etch-Stop Nitride: Impact on Deep-Submicron Transistor Performance", Microelectronics and Reliability, Elsevier Science Ltd., GB, vol. 42, no. 2, February 2002, pages 201-209.	<input type="checkbox"/>
BTL	3	S. Ito et al., "Mechanical Stress Effect of Etch-Stop Nitride and its Impact on Deep Submicron Transistor Design", IEDM Technical Digest, 2000 IEEE, pp. 10.7.1-10.7.4.	<input type="checkbox"/>

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#### EXAMINER SIGNATURE

Examiner Signature	/Benjamin Tzu-Hung Liu	Date Considered/	(09/13/2006)
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<sup>1</sup> See Kind Codes of USPTO Patent Documents at [www.USPTO.GOV](http://www.USPTO.GOV) or MPEP 901.04. <sup>2</sup> Enter office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>3</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>4</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>5</sup> Applicant is to place a check mark here if English language translation is attached.

INFORMATION DISCLOSURE STATEMENT  
(Use several sheets if necessary)

Docket Number (Optional)

FIS920020105

Application Number

To be assigned

10/536483

Applicant(s)

Doris, et al.

Filing Date

11/25/02

Group Art Unit

2826

To be assigned

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		3,602,841	8-31-71	McGroddy			
		4,665,415	5-12-87	Esaki, et al.			
		4,853,076	8-1-89	Tsaur, et al.			
		4,855,245	8-8-89	Neppl, et al.			
▼		4,952,524	8-28-90	Lee, et al.			

## U.S. PATENT APPLICATION PUBLICATIONS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		US 2001/0009784 A1	7-26-01	Ma, et al.			
		US 2002/0063292 A1	5-30-02	Armstrong, et al.			
		US 2002/0074598 A1	6-20-02	Doyle, et al.			
▼		US 2002/0086472	7-4-02	Roberds, et al.			

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
BTL		JP64-76755	03-1989	Japan				

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

BTL		Kern Rim, et al., "Transconductance Enhancement in Deep Submicron Strained-Si n-MOSFETs". International Electron Devices Meeting, 26, 8, 1, IEEE, September 1998.
BTL		Kern Rim, et al., "Characteristics and Device Design of Sub-100 nm Strained Si N- and PMOSFETs." 2002 Symposium on VLSI Technology Digest of Technical Papers, IEEE, pp. 98-99.

EXAMINER /Benjamin Tzu-Hung Liu DATE CONSIDERED / (09/13/2006)

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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				Docket Number (Optional)	Application Number 107556483 To be assigned		
				FIS920020105			
				Applicant(s)	Doris, et al.		
				Filing Date	Group Art Unit 11/25/02 2826 To be assigned		
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		4,958,213	9-18-90	Eklund, et al.			
BTL		5,006,913	4-9-91	Sugahara, et al.			
BTL		5,060,030	10-22-91	Hoke, et al.			
BTL		5,081,513	1-14-92	Jackson, et al.			
BTL		5,108,843	4-28-92	Ohtaka, et al.			
U.S. PATENT APPLICATION PUBLICATIONS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		US 2002/0086497 A1	7-4-02	Kwok			
BTL		US 2002/0090791 A1	7-11-02	Doyle, et al.			
BTL		US 2003/0032261 A1	2-13-03	Yeh, et al.			
BTL		US 2003/0040158 A1	2-27-03	Saitoh			
FOREIGN PATENT DOCUMENTS							
REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
BTL		Gregory Scott, et al., "NMOS Drive Current Reduction Caused by Transistor Layout and Trench Isolation Induced Stress." International Electron Devices Meeting, 34.4.1, IEEE, September 1999.					
BTL		F. Ootsuka, et al., "A Highly Dense, High-Performance 130um Node CMOS Technology for Large Scale System-on-a-Chip Application." International Electron Devices Meeting, 23.5.1, IEEE, April 2000.					
EXAMINER / Benjamin Tzu-Hung Liu				DATE CONSIDERED / (09/13/2006)			
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			Applicant(s) <b>Doris, et al.</b>	Filing Date <b>11/25/02</b>

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		5,134,085	7-28-92	Gilgen, et al.			
BTL		5,310,446	5-10-94	Konishi, et al.			
BTL		5,354,695	10-11-94	Leedy			
BTL		5,371,399	12-6-94	Burroughes, et al.			
BTL		5,391,510	2-21-95	Hsu, et al.			

## U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		US 2003/0057184 A1	3-27-03	Yu, et al.			
BTL		US 2003/0067035 A1	4-10-03	Tews, et al.			

## FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Transitions	
						YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

BTL		Shinya Ito, et al., "Mechanical Stress Effect of Etch-Stop Nitride and its Impact on Deep Submicron Transistor Design." International Electron Devices Meeting, 10.7.1, IEEE, April 2000.
BTL		A. Shimizu, et al., "Local Mechanical-Stress Control (LMC): A New Technique for CMOS-Performance Enhancement." International Electron Devices Meeting, IEEE, March 2001.

EXAMINER	/Benjamin Tzu-Hung Liu	DATE CONSIDERED / (09/13/2006)
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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)			Docket Number (Optional)		Application Number 107536483 To be assigned		
			PIS920020105 Applicant(s) Doris, et al.		Filing Date 11/25/02 CROSS ATT'D 2826 To be assigned		
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		5,459,346	10-17-95	Asakawa, et al.			
BTL		5,471,948	12-5-95	Burroughes, et al.			
BTL		5,557,122	9-17-96	Shrivastava, et al.			
BTL		5,561,302	10-1-96	Candelaria			
BTL		5,565,697	10-15-96	Asakawa, et al.			
U.S. PATENT APPLICATION PUBLICATIONS							
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
FOREIGN PATENT DOCUMENTS							
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation YES      NO
OTHER DOCUMENTS      (Including Author, Title, Date, Pertinent Pages, Etc.)							
BTL		K. Ota, et al., "Novel Locally Strained Channel Technique for High Performance 55nm CMOS." International Electron Devices Meeting, 2.2.1, IEEE, February 2002.					
BTL		G. Zhang, et al., "A New 'Mixed-Mode' Reliability Degradation Mechanism in Advanced Si and SiGe Bipolar Transistors." IEEE Transactions on Electron Devices, vol. 49, no. 12, December 2002, pp. 2151-56.					
EXAMINER /Benjamin Tzu-Hung Liu			DATE CONSIDERED / (09/13/2006)				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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10756483

INFORMATION DISCLOSURE STATEMENT  
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Document Status (Open/Close) Application Number  
PIS920020105 To be assigned  
Applicant(s)  
Doris, et al.  
Filing Date  
11/25/02 Group Art Unit  
To be assigned 2826

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		5,571,741	11-5-96	Leedy			
BTL		5,592,007	1-7-97	Leedy			
BTL		5,592,018	1-7-97	Leedy			
BTL		5,670,798	9-23-97	Schetzina			
BTL		5,679,965	10-21-97	Schetzina			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

OTHER DOCUMENTS (Including Author, Tide, Date, Pertinent Pages, Etc.)

BTL		H.S. Momose, et al., "Temperature Dependence of Emitter-Base Reverse Stress Degradation and Its Mechanism Analyzed by MOS Structures." Paper 6.2, pp. 140-143.
BTL		C.J. Huang, et al., "Temperature Dependence and Post-Stress Recovery of Hot Electron Degradation Effects in Bipolar Transistors." IEEE 1991 Bipolar Circuits and Technology Meeting 7.5, pp. 170-173.

EXAMINER /Benjamin Tzu-Hung Liu DATE CONSIDERED / (09/13/2006)

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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)			Docket Number (Optional)	Application Number
			FIS920020105	107536483 To be assigned
Applicant(s) Doris, et al.			Filing Date	Group Art Unit
			11/25/02	2826 To be assigned

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REP	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		5,683,934	11-4-97	Candelaria			
BTL		5,840,593	11-24-98	Leedy			
BTL		5,861,651	1-19-99	Brasen, et al.			
BTL		5,880,040	3-9-99	Sun, et al.			
BTL		5,940,716	8-17-99	Jin, et al.			

## U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REP	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

## FOREIGN PATENT DOCUMENTS

	REP	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

BTL		S.R. Sheng, et al., "Degradation and Recovery of SiGe HBTs Following Radiation and Hot-Carrier Stressing." Pp. 14-15.
BTL		Z. Yang, et al., "Avalanche Current Induced Hot Carrier Degradation in 200 GHz SiGe Heterojunction Bipolar Transistors." Pp. 1-5.

EXAMINER	/Benjamin Tzu-Hung Liu	DATE CONSIDERED	/ (09/13/2006)
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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				Docket Number (Optional) <b>FIS920020105</b>	Application Number <b>107536483</b>		
				Applicant(s) <b>Doris, et al.</b>	Filing Date <b>11/25/02</b>	Group Art Unit <b>2826</b>	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		5,940,736	8-17-99	Brady, et al.			
BTL		5,946,559	8-31-99	Leedy			
BTL		5,960,297	9-28-99	Saki			
BTL		5,989,978	11-23-99	Peidous			
BTL		6,008,126	12-28-99	Leedy			
U.S. PATENT APPLICATION PUBLICATIONS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
FOREIGN PATENT DOCUMENTS							
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translates YES      NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
BTL		H. Li, et al., "Design of W-Band VCOs with High Output Power for Potential Application in 77 GHz Automotive Radar Systems." 2003 IEEE GaAs Digest, pp. 263-66.					
BTL		H. Wurzer, et al., "Annealing of Degraded n-pn-Transistors- Mechanisms and Modeling." IEEE Transactions on Electron Devices, vol. 41, no. 4, April 1994, pp. 533-38.					
EXAMINER /Benjamin Tzu-Hung Liu				DATE CONSIDERED / (09/13/2006)			
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				FIS920020105				
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				Filing Date		Group Art Unit		
				11/25/02		2826 To be assigned		
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EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME		CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		6,025,280	2-15-00	Brady, et al.				
BTL		6,046,464	4-4-00	Schetzina				
BTL		6,066,545	5-23-00	Doshi, et al.				
BTL		6,090,684	7-18-00	Ishitsuka, et al.				
BTL		6,107,143	8-22-00	Park, et al.				
U.S. PATENT APPLICATION PUBLICATIONS								
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME		CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
FOREIGN PATENT DOCUMENTS								
REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation		
						YES	NO	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)								
BTL		B. Doyle, et al., "Recovery of Hot-Carrier Damage in Reoxidized Nitrided Oxide MOSFETs." IEEE Electron Device Letters, vol. 13, no. 1, January 1992, pp. 38-40.						
BTL		H.S. Momose, et al., "Analysis of the Temperature Dependence of Hot-Carrier-Induced Degradation in Bipolar Transistors for Bi-CMOS." IEEE Transactions on Electron Devices, vol. 41, no. 6, June 1994, pp. 978-987.						
EXAMINER			/ Benjamin Tzu-Hung Liu		DATE CONSIDERED / (09/13/2006)			
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)			Docket Number (Optional)	Application No. 10/536,483 To be assigned	
			PIS920020105 Applicant(s) Doris, et al.	Filing Date 11/25/02	Group Art Unit 2826 To be assigned

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		6,117,722	9-12-00	Wuu, et al.			
BTL		6,133,071	10-17-00	Nagai			
BTL		6,165,383	12-26-00	Chou			
BTL		6,221,735	4-24-01	Manley, et al.			
BTL		6,228,694	5-8-01	Doyle, et al.			

## U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

## FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

EXAMINER	/ Benjamin Tzu-Hung Liu	DATE CONSIDERED	/ (09/13/2006)
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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				Docket Number (Optional) <b>FIS920020105</b>	Application Number <b>107536483</b> To be assigned		
				Applicant(s) <b>Doris, et al.</b>	Filing Date <b>11/25/02</b>		
				Group Art Unit	To be assigned		
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		6,246,095	6-12-01	Brady, et al.			
BTL		6,255,169	7-3-01	Li, et al.			
BTL		6,261,964	7-17-01	Wu, et al.			
BTL		6,265,317	7-24-01	Chiu, et al.			
BTL		6,274,444	8-14-01	Wang			
U.S. PATENT APPLICATION PUBLICATIONS							
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
FOREIGN PATENT DOCUMENTS							
REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Transition	
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER <b>/Benjamin Tzu-Hung Liu</b>				DATE CONSIDERED <b>/ (09/13/2006)</b>			
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				Applicant(s) Doris, et al.	Filing Date 11/25/02	Group Art Unit 2826 To be assigned	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		6,281,532	8-28-01	Doyle, et al.			
BTL		6,284,623	9-4-01	Zhang, et al.			
BTL		6,284,626	9-4-01	Kim			
BTL		6,319,794	11-20-01	Akatsu, et al.			
BTL		6,361,885	3-26-02	Chou			
U.S. PATENT APPLICATION PUBLICATIONS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
FOREIGN PATENT DOCUMENTS							
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation YES      NO
OTHER DOCUMENTS      (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER      /Benjamin Tzu-Hung Liu				DATE CONSIDERED		/ (09/13/2006)	
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INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)			Docket Number (Optional) PIS920020105		Application Number 10/1536483 To be assigned			
			Applicant(s) Doris, et al.		Filing Date 11/25/02			
			Group Art Unit		To be assigned			
			U.S. PATENT DOCUMENTS					
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
BTL		6,362,082	3-26-02	Doyle, et al.				
BTL		6,368,931	4-9-02	Kuhn, et al.				
BTL		6,403,486	6-11-02	Lou				
BTL		6,403,975	6-11-02	Brunner, et al.				
BTL		6,406,973	6-18-02	Lee				
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	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)								
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BTL		6,461,936	10-8-02	von Ehrenwall			
BTL		6,476,462	11-5-02	Shimizu, et al.			
BTL		6,483,171	11-19-02	Forbes, et al.			
BTL		6,493,497	12-10-02	Ramdani, et al.			
BTL		6,498,358	12-24-02	Lach, et al.			
U.S. PATENT APPLICATION PUBLICATIONS							
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FOREIGN PATENT DOCUMENTS							
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation YES      NO
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>							
EXAMINER      /Benjamin Tzu-Hung Liu				DATE CONSIDERED      / (09/13/2006)			
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				Docket Number (Optional) PIS920020105	Application Number To be assigned <b>101536483</b>		
				Applicant(s) Doris, et al.	Filing Date 11/25/02	Group Art Unit To be assigned	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		6,501,121	12-31-02	Yu, et al.			
BTL		6,506,652	1-14-03	Jan, et al.			
BTL		6,509,618	1-21-03	Jan, et al.			
BTL		6,521,964	2-18-03	Jan, et al.			
BTL		6,531,369	3-11-03	Ozkan, et al.			
U.S. PATENT APPLICATION PUBLICATIONS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
FOREIGN PATENT DOCUMENTS							
REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>							
EXAMINER / Benjamin Tzu-Hung Liu				DATE CONSIDERED		/ (09/13/2006)	
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				Docket Number (Optional) <b>FIS920020105</b>	Application Number <b>10/536483</b> To be assigned			
				Applicant(s) <b>Doris, et al.</b>	Filing Date <b>11/25/02</b>	Group Art Unit <b>2826</b> To be assigned		
U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
BTL		<b>6,531,740</b>	<b>3-11-03</b>	<b>Bosco, et al.</b>				
BTL		<b>6,621,392</b>	<b>9-16-03</b>	<b>Volant, et al.</b>				
BTL		<b>6,635,506</b>	<b>10-21-03</b>	<b>Volant, et al.</b>				
U.S. PATENT APPLICATION PUBLICATIONS								
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
FOREIGN PATENT DOCUMENTS								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Trademarks	
							YES	NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)								
EXAMINER <b>/Benjamin Tzu-Hung Liu</b>				DATE CONSIDERED		<b>/ (09/13/2006)</b>		
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

1000 Docket No./DPA 21 MAY 2005

INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)		Docket Number (Optional) <b>FIS92002018</b>	Application Number <b>107536483</b> To be assigned
		Applicant(s) <b>Doris, et al.</b>	
		Filing Date <b>11/25/02</b>	Group Art Unit <b>2826</b> To be assigned

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		6,342,410	1-29-02	Yu			
BTL		6,413,802	7-2-02	Hu, et al.			
BTL		6,433,609	8-13-02	Voldman			
BTL		6,458,662	10-1-02	Yu			

## U.S. PATENT APPLICATION PUBLICATIONS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

## FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

## OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER /Benjamin Tzu-Hung Liu DATE CONSIDERED / (09/13/2006)

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